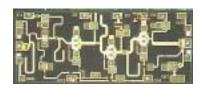
Description

The RMWD24001 is a 4-stage GaAs MMIC amplifier designed as a 21 to 26.5 GHz Driver Amplifier for use in point to point radios, point to multi-point communications, LMDS, and other millimeter wave applications. In conjunction with other Raytheon amplifiers, multipliers and mixers it forms part of a complete 23 and 26 GHz transmit/receive chipset. The RMWD24001 utilizes Raytheon's 0.25µm power PHEMT process and is sufficiently versatile to serve in a variety of driver amplifier applications.

Features

- 4 mil substrate
- Small-signal gain 23 dB (typ.)
- 1dB compressed Pout 17 dBm (typ.)
- Voltage detector included to monitor Pout
- Chip size 2.85 mm x 1.2 mm



Maximum Ratings

<u>Parameter</u>	Symbol	Value	Unit
Positive DC voltage (+4 V Typical)	Vd	+6	Volts
Negative DC voltage	Vg	-2	Volts
Simultaneous (Vd - Vg)	Vdg	8	Volts
Positive DC Current	I _D	345	mA
RF Input Power (from 50 Ω source)	P_{IN}	+8	dBm
Operating Baseplate Temperature	T _C	-30 to +85	°C
Storage Temperature Range	T_{stg}	-55 to +125	°C
Thermal Resistance	R_{JC}^{JS}	42	°C/W
(Channel to Backside)	00		

Electrical
Characteristics
(At 25°C),
50 Ω system,
Vd=+4 V,
Quiescent
Current
Idq=240 mA

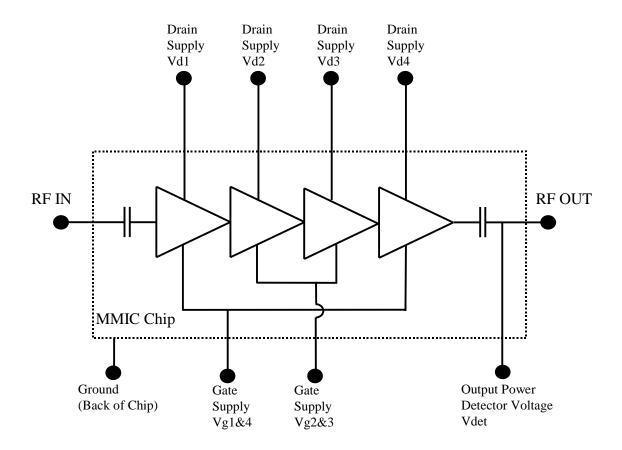
,				
<u>Parameter</u>	Min	Тур	Max	Unit
Frequency Range	21		26.5	GHz
Gate Supply Voltage (Vg) (Note 1)		-0.4		V
Gain Small Signal at Pin=-12 dBm	20	23		dB
Gain Variation vs. Frequency		3		dB
Gain at 1dB Compression		22		dB
Power Output at P1dB (Pin=-6 dBm)	13	17		dBm
Drain Current at Pin=-12 dBm		240		mΑ
Drain Current at 1dB Compression		265		mΑ
Input Return Loss (Pin=-12 dBm)		10		dB
Output Return Loss (Pin=-12 dBm)		12		dB
OIP3		TBD		dBm
Noise Figure		TBD		dB
Detector Voltage		TBD		V

Note 1:

Typical range of gate voltage is -0.7 to -0.1 V to set Idq of 240 mA.

Raytheon reserves the right to update or change specifications without notice.

Functional Block Diagram

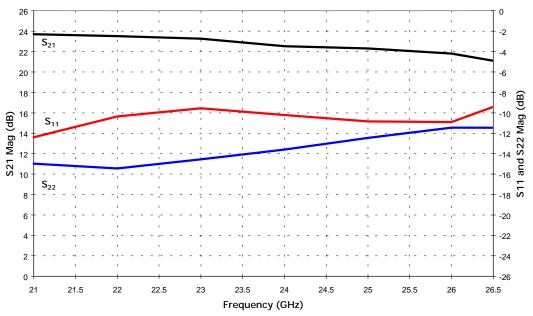


Note: Detector delivers 0.1 V DC into 3k Ω load resistor for >+7 dBm output power. If output power level detection is not desired, do not make connection to detector bond pad.

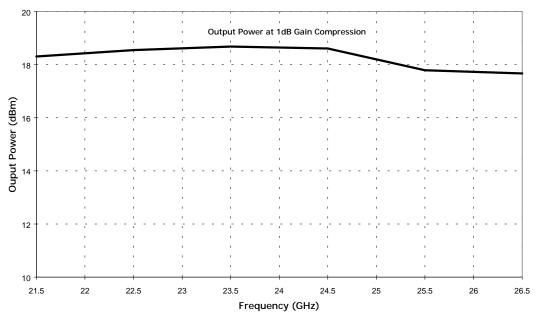
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Performance Data

RMWD24001 26 GHz Driver Amplifier. Typical On-Wafer Performance. $I_{DQ} = 210 \text{ mA V}_{DD} = 4 \text{ V}$



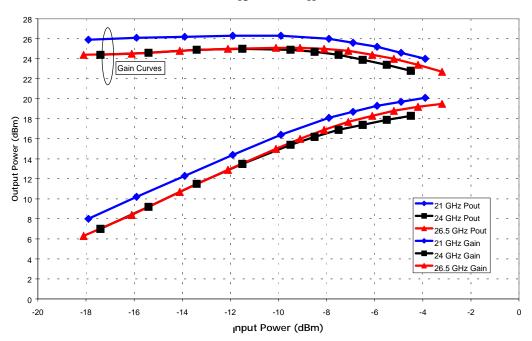
RMWD24001 26 GHz Driver Typical Output Power at 1 dB Gain Compression. Measured On-Wafer I $_{\rm PQ}=240$ mA $\rm V_{DD}=4~V$



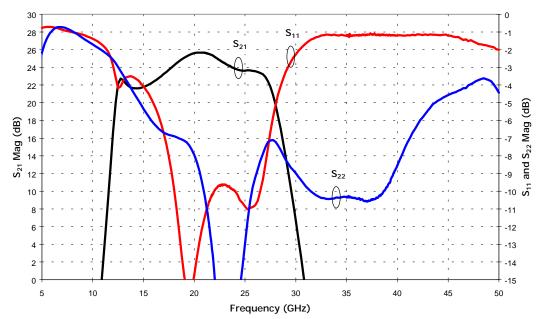
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Performance Data

RMWL24001 Typical Power Saturation Curves. Measurements Include 50 Ohm Test Fixture. I $_{\rm DQ}=240$ mA $\rm V_{\rm DD}=4.0~V$



RMWL24001 Driver Amplfier Typical WideBand S-Parameters. Measurements Include 50 Ohm Test Fixture. $I_{DQ} = 240 \text{ mA V}_{DD} = 4 \text{ V}$



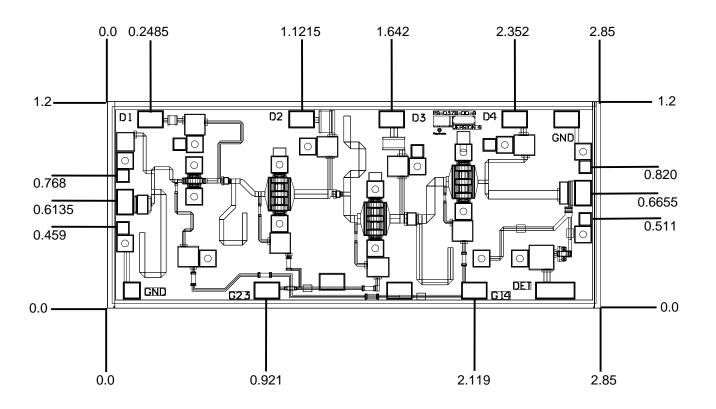
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Application Information

Caution: This is an ESD sensitive device

Chip Layout and Bond Pad Locations

Chip Size is 2.85 mm x 1.2 mm Typical. Back of chip is RF and DC ground

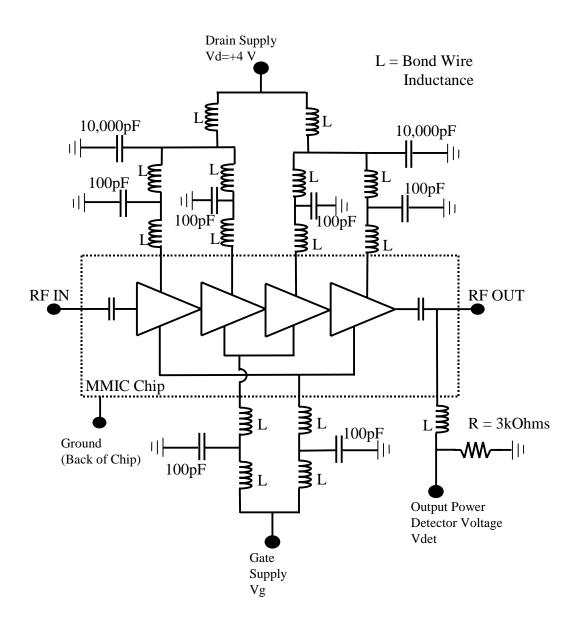


Dimensions in mm

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Application Information

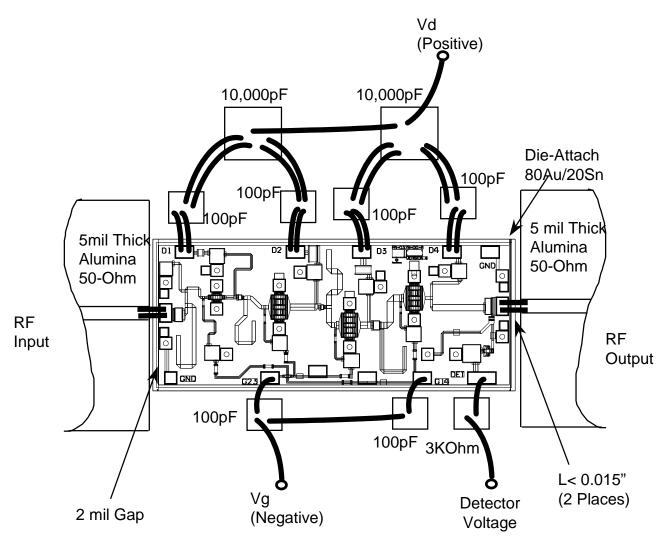
Recommended Application Schematic Circuit Diagram



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Application Information

Recommended Assembly Diagram



Note: Use 0.003" by 0.0005" Gold Ribbon for bonding. RF input and output bonds should be less than 0.015" long with stress relief.

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Application Information

CAUTION: THIS IS AN ESD SENSITIVE DEVICE.

Chip carrier material should be selected to have GaAs compatible thermal coefficient of expansion and high thermal conductivity such as copper molybdenum or copper tungsten. The chip carrier should be machined, finished flat, plated with gold over nickel and should be capable of withstanding 325°C for 15 minutes.

Die attachment should utilize Gold/Tin (80/20) eutectic alloy solder and should avoid hydrogen environment for PHEMT devices. Note that the backside of the chip is gold plated and is used as RF and DC ground.

These GaAs devices should be handled with care and stored in dry nitrogen environment to prevent contamination of bonding surfaces. These are ESD sensitive devices and should be handled with appropriate precaution including the use of wrist grounding straps. All die attach and wire/ribbon bond equipment must be well grounded to prevent static discharges through the device.

Recommended wire bonding uses 3 mils wide and 0.5 mil thick gold ribbon with lengths as short as practical allowing for appropriate stress relief. The RF input and output bonds should be typically 0.012" long corresponding to a typically 2 mil between the chip and the substrate material.

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Tel: 978-684-8663 Fax: 978-684-8646 www.raytheon.com/micro Revised March 14, 2001

Application Information

Recommended Procedure for Biasing and Operation

Caution: This is an ESD sensitive device

Caution: Loss of gate voltage (Vgs) while drain voltage (Vds) is present may damage the amplifier chip.

The following sequence of steps must be followed to properly test the amplifier:

Step 1: Turn off RF input power.

Step 2: Connect the DC supply grounds to the grounds of the chip carrier.

Slowly apply negative gate bias supply voltage of -1.5 V to Vgs.

Step 3: Slowly apply positive drain bias supply voltage of +4 V to Vds.

Step 4: Adjust gate bias voltage to set the quiescent current of Idq=240 mA.

Step 5: After the bias condition is established, RF input signal may now be applied at the

appropriate frequency band.

Step 6: Follow turn-off sequence of:

(i) Turn off RF input power, (ii) Turn down and off drain voltage (Vds), (iii) Turn

down and off gate bias voltage (Vgs).

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